

<b>Notice of References Cited</b>	Application/Control No. 10/706,538		Applicant(s)/Patent Under Reexamination LACKEY, DAVID E.	
	Examiner Naum B Levin		Art Unit 2825	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,604,227	08-2003	Foltin et al.	716/6
	B	US-2002/0100006	07-2002	Kosugi	716/6
	C	US-6,327,557	12-2001	Croix	703/14
	D	US-6,223,333	04-2001	Kuribayashi et al.	716/12
	E	US-5,657,239	08-1997	Grodstein et al.	716/6
	F	US-5,535,223	07-1996	Horstmann et al.	714/744
	G	US-5,696,694	12-1997	Khouja et al.	716/5
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Savaria, Y. et al., "Automatic test point insertion for pseudo-random testing", Circuits and Systems, 1991., IEEE International Symposium on , 11-14 June 1991 Pages:1960 - 1963 vol.4			
	V	Rao, N.S.V. et al., "Computational Complexity of Test-Point Insertions and Decompositions", VLSI Design, 1992. Proceedings. The Fifth International Conference on , January 4-7, 1992 Pages:233 - 238			
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.